

Notice of References Cited	Application/Control No. 10/711,168		Applicant(s)/Patent Under Reexamination BREILAND ET AL.	
	Examiner Russell Frejd		Art Unit 2128	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0061571	03-2003	Buffet et al.	716/1
*	B	US-6,584,596	06-2003	Buffet et al.	716/1
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	SHUMAKHER et al., E. On the Noise Properties of Injection-Locked Oscillators, IEEE Transactions on Microwave Theory and Techniques, Vol. 52, No. 5, May 2004, pp. 1523-37.
	V	ROSENBAUM et al., E. Silicon Dioxide Breakdown Lifetime Enhancement Under Bipolar Bias Conditions, IEEE Transaction on Electron Devices, Vol. 40 No. 12, December 1993, pp. 2287-95.
	W	KUST ET AL., E. Influence of Solvent Nature on the Electrochemical Parameters of Electrical Double Layer Capacitors, Journal of Electroanalytical Chemistry, Vol. 562, No. 1, January 2004, pp. 33-42.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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